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•	Designed Specifically for High-Speed
	Memory Decoders and Data Transmission
	Systems

- Incorporates Three Enable Inputs to Simplify Cascading and/or Data Reception
- Center-Pin V<sub>CC</sub> and GND Configurations Minimize High-Speed Switching Noise
- *EPIC*<sup>™</sup> (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline (D) and Thin Shrink Small-Outline (PW) Packages, and Standard Plastic 300-mil DIPs (N)

D, N,	D, N, OR PW PACKAGE (TOP VIEW)										
Y1 Y2 Y3 GND Y4 Y5 Y6 Y7	3 4 5	16 15 14 13 12 11 10 9	] Y0 ] A ] C ] C ] G1 ] G2A ] G2B								

## description

The 74AC11138 circuit is designed to be used in high-performance memory-decoding or data-routing applications requiring very short propagation delay times. In high-performance memory systems, this decoder can be used to minimize the effects of system decoding. When employed with high-speed memories utilizing a fast enable circuit, the delay times of this decoder and the enable time of the memory are usually less than the typical access time of the memory. This means that the effective system delay introduced by the decoder is negligible.

The conditions at the binary-select (A, B, C) inputs and the three enable (G1, G2A, G2B) inputs select one of eight output lines. Two active-low and one active-high enable inputs reduce the need for external gates or inverters when expanding. A 24-line decoder can be implemented without external inverters and a 32-line decoder requires only one inverter. An enable input can be used as a data input for demultiplexing applications.

The 74AC11138 is characterized for operation from -40°C to 85°C.	The 74AC11138 is characterized for operation from	−40°C to 85°C.
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ENABLE INPUTS SELECT INPUTS				OUTPUTS									
G1	G2A	G2B	С	В	Α	Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7
Х	Н	Х	Х	Х	Х	Н	Н	Н	Н	Н	Н	Н	Н
Х	Х	н	Х	Х	Х	н	Н	н	Н	Н	Н	Н	Н
L	Х	Х	Х	Х	Х	н	Н	Н	Н	Н	Н	Н	Н
н	L	L	L	L	L	L	Н	Н	Н	Н	Н	Н	Н
н	L	L	L	L	н	н	L	н	Н	Н	Н	Н	Н
н	L	L	L	Н	L	н	Н	L	Н	Н	Н	Н	Н
н	L	L	L	Н	н	н	Н	н	L	Н	Н	Н	Н
н	L	L	н	L	L	н	Н	н	Н	L	Н	Н	Н
н	L	L	н	L	Н	н	Н	Н	Н	Н	L	Н	Н
н	L	L	н	Н	L	н	Н	н	Н	Н	Н	L	Н
н	L	L	н	н	н	н	н	н	н	н	н	н	L

FUNCTION TABLE



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## logic symbols (alternatives)<sup>†</sup>



<sup>†</sup> These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)





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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

	5 V 5 V mA mA mA MA W W
	W
Storage temperature range, T <sub>stg</sub>	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

### recommended operating conditions

			MIN	NOM	MAX	UNIT
Vcc	Supply voltage		3	5	5.5	V
		V <sub>CC</sub> = 3 V	2.1			
VIH	High-level input voltage	$V_{CC} = 4.5 V$	3.15			V
		V <sub>CC</sub> = 5.5 V	3.85			
		V <sub>CC</sub> = 3 V			0.9	
VIL	VIL Low-level input voltage				1.35	V
		V <sub>CC</sub> = 5.5 V			1.65	
VI	Input voltage				VCC	V
Vo	Output voltage		0		VCC	V
		V <sub>CC</sub> = 3 V			-4	
ЮН	High-level output current	V <sub>CC</sub> = 4.5 V			-24	mA
		V <sub>CC</sub> = 5.5 V			-24	
		V <sub>CC</sub> = 3 V			12	
IOL	Low-level output current	$V_{CC} = 4.5 V$			24	mA
		V <sub>CC</sub> = 5.5 V			24	
$\Delta t/\Delta v$	Input transition rise or fall rate		0		10	ns/V
ТĄ	Operating free-air temperature		-40		85	°C



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electrical characteristics	over	recommended	operating	free-air	temperature	range	(unless
otherwise noted)					•	•	•

PARAMETER	TEST CONDITIONS		T	<b>₄ = 25°C</b>	;	MIN MAX		UNIT
FARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	IVIIIN	WAA	UNIT
		3 V	2.9			2.9		
	I <sub>OH</sub> = -50 μA	4.5 V	4.4			4.4		
		5.5 V	5.4			5.4		
VOH	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.48		V
		4.5 V	3.94			3.8		
	I <sub>OH</sub> = -24 mA	5.5 V	4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
		3 V			0.1		0.1	
	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1	
		5.5 V			0.1		0.1	
VOL	I <sub>OL</sub> = 12 mA	3 V			0.36		0.44	V
	lo: - 24 mA	4.5 V			0.36		0.44	
	I <sub>OL</sub> = 24 mA	5.5 V			0.36		0.44	
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65	
lj	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1	μA
ICC	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5 V			4		40	μA
Ci	$V_I = V_{CC}$ or GND	5 V		3.5				pF

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO		Т	<b>₄ = 25°C</b>	;	MIN	MAX	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX		WAA	
<sup>t</sup> PLH		Any Y	1.5	8.3	10.2	1.5	11.4	ns
<sup>t</sup> PHL	A, B, C		1.5	8.9	10.9	1.5	12.2	115
<sup>t</sup> PLH	C1	Any V	1.5	7.2	9.2	1.5	10.2	20
<sup>t</sup> PHL	G1	Any Y	1.5	7.3	9.4	1.5	10.5	ns
<sup>t</sup> PLH	G2A, G2B	Any V	1.5	8.2	10.4	1.5	11.5	20
<sup>t</sup> PHL		Any Y	1.5	8.3	10.4	1.5	11.6	ns

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO		T,	ק = 25°C	;	MIN	MAX	UNIT
FARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX		WAA	UNIT
<sup>t</sup> PLH		Any Y	1.5	5.7	7.3	1.5	8.1	20
<sup>t</sup> PHL	A, B, C		1.5	6.2	7.9	1.5	8.8	ns
<sup>t</sup> PLH	G1	Any Y	1.5	5.1	6.9	1.5	7.5	ns
<sup>t</sup> PHL	GI	Any i	1.5	5.2	6.9	1.5	7.7	115
<sup>t</sup> PLH	G2A, G2B	Any Y	1.5	5.8	7.6	1.5	8.3	ns
<sup>t</sup> PHL			1.5	5.6	7.5	1.5	8.3	115



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## operating characteristics, $V_{CC}$ = 5 V, $T_A$ = 25°C

	PARAMETER		TEST CONDITIONS		
C <sub>pd</sub>	Power dissipation capacitance per gate	C <sub>L</sub> = 50 pF,	f = 1 MHz	51	pF

## PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

B. Input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub> = 3 ns, t<sub>f</sub> = 3 ns.

C. The outputs are measured one at a time with one input transition per measurement.

### Figure 1. Load Circuit and Voltage Waveforms



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Figure 3. 32-Bit Decoding Scheme



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